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		149 (Modified)		First Named Inventor	Ronald F. Rykowski		
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				Examiner Name			
Sheet	1	of	11	Attorney Docket No.	40678-8002US		

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EXAMINER	DATE CONSIDERED
Rodres	8/4/05
*EXAMINER:	Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not
i	considered. Include conv. of this form with next communication to analisation(s)